

<b>SUBSTITUTE FORM PTO-1449A</b> <b>LIST OF PATENTS AND</b> <b>APPLICANT'S INFORMATION</b> <b>DISCLOSURE STATEMENT</b>		Atty Docket: Serial No.: Applicant: Filing Date: Group:	02AG49153548 Not Yet Assigned ALBERICI Herewith	10574868 - GAU: 4183
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**U.S. PATENT DOCUMENTS**

Examiner Initials		Document Number	Date	Name	Class	Sub Class	Filing Date
	AA	6,104,029	8/15/00	Coxon et al.	250	305	
	AB	2001/0052744	12/20/01	Tsuno	313	364	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	Class	Sub Class	Translation
	AJ						
	AK						
	AL						

**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

	AM	Hayashi et al., Energy Loss Near-Edge Structure for Materials Containing Light Elements by Reflection Electron Energy Loss Spectroscopy, Applied Physics Letters, American Institute of Physics, New York, Vol. 66, No. 1, January 2, 1995, Pages 25-27
	AN	Ertl et al., Low Energy Electrons and Surface Chemistry, 1985, VCH Verlagsgesellschaft MBH, Weinheim, Germany, Pages 6-25, 185-200, 285-291
	AO	Mook et al., Electrostatic In-Line Monochromator for Schottky Field Emission Gun, Institute of Physics Conference Series, IOP Publishing, No. 153, 1997, Pages 81-84
	AP	Browning et al., A Digital Scanning Auger Electron Microscope Incorporation a Concentric Hemispherical Analyser, Proceedings of the Royal Society of London, Series A, Mathematical and Physical Sciences, Royal Society of London, Vol. 357, No. 1689, 1977, Pages 213-230
	AQ	Henrard et al., Electron-Energy-Loss Spectroscopy of Plasmon Excitations in Concentric-Shell Fullerenes, Physical Review B (Condensed Matter) APS Through AIP USA, Vol. 59, No. 8, February 15, 1999, Pages 5832-5836
	AR	

<b>EXAMINER:</b>	/Hanway Chang/	<b>DATE CONSIDERED:</b>	02/17/2009
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /H.C./